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(Modified)		PATENT AND TRAD	EMARK OFFICE	241723US2S	New Application				
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LIST OF	REFE	RENCES CITED BY APP	PLICANT	Shigeru NAGASAKA, et al.					
				FILING DATE		GROUP			
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. U.S. PATENT DOCUMENTS									
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OTHER REFERENCES (Including Author, Title, Date, PertInent Pages, etc.)									
91:05	AW	M. Togo, et al., "Low-Leakage and Highly-Reliable 1.5nm SiON Gate-Dieletric Using Radical Oxynitridation for Sub-0.1µm CMOS", Silicon Systems Research Labs., NEC.C (Japan), 2000 SYMPOSIUM ON VLSI TECHNOLOGY DIGEST OF TECHNICAL PAPERS, 2000, pgs. 116-117							
1. 1/1	AX	Wel-Hua Liu, et al., "A-2 Transistor Source-select (2TS) Flash EEPROM for 1.8V-Only Applications", Semiconductor Technologies Laboratory, Motorola Inc., Austin, Texas, NON-VOLATILE SEMICONDUCTOR MEMORY WORKSHOPS 4.1, 1997, pgs. 1-3							
<i></i>	AY	Toori, pgs. 1-0							
	AZ	Additional References sheet(s) attached							
						1:7			
Examiner Date Considered 4/28/05									
*Examiner. Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									